

Notice of References Cited	Application/Control No. 10/084,019		Applicant(s)/Patent Under Reexamination TIEDEMANN ET AL.	
	Examiner VENKATESH HALIYUR		Art Unit 2476	Page 1 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,351,274 A	09-1994	Chennakeshu et al.	375/347
*	B	US-5,406,593 A	04-1995	Chennakeshu et al.	375/376
*	C	US-6,154,489 A	11-2000	Kleider et al.	375/221
*	D	US-2001/0055311 A1	12-2001	Trachewsky et al.	370/445
*	E	US-2002/0006136 A1	01-2002	Mallory et al.	370/466
*	F	US-2002/0012343 A1	01-2002	Holloway et al.	370/389
*	G	US-2002/0026523 A1	02-2002	Mallory et al.	709/236
*	H	US-2002/0027886 A1	03-2002	Fischer et al.	370/255
*	I	US-2002/0041570 A1	04-2002	Ptasinski et al.	370/252
*	J	US-2002/0046382 A1	04-2002	YANG, GANNING	714/758
*	K	US-2002/0042836 A1	04-2002	Mallory, Tracy D.	709/232
*	L	US-2002/0057713 A1	05-2002	Bagchi et al.	370/468
*	M	US-2002/0057717 A1	05-2002	Mallory, Tracy D.	370/503

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 1801997 A2	06-2007	European Patent	LUNDBY et al.	H04B 07/005
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/084,019		Applicant(s)/Patent Under Reexamination TIEDEMANN ET AL.	
	Examiner VENKATESH HALIYUR		Art Unit 2476	Page 2 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0080886 A1	06-2002	Ptasinski et al.	375/295
*	B	US-6,427,219 B1	07-2002	Yang, Ganning	714/758
*	C	US-2002/0110088 A1	08-2002	Lundby et al.	370/252
*	D	US-2002/0131441 A1	09-2002	Trachewsky et al.	370/441
*	E	US-2002/0163932 A1	11-2002	Fischer et al.	370/465
*	F	US-2003/0043732 A1	03-2003	Walton et al.	370/208
*	G	US-2003/0128658 A1	07-2003	Walton et al.	370/208
*	H	US-2003/0125040 A1	07-2003	Walton et al.	455/454
*	I	US-2003/0157900 A1	08-2003	Gaal et al.	455/69
*	J	US-2003/0206559 A1	11-2003	Trachewsky et al.	370/509
*	K	US-6,751,187 B2	06-2004	Walton et al.	370/210
*	L	US-6,877,043 B2	04-2005	Mallory et al.	709/251
*	M	US-6,882,634 B2	04-2005	Bagchi et al.	370/338

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/084,019		Applicant(s)/Patent Under Reexamination TIEDEMANN ET AL.	
	Examiner VENKATESH HALIYUR		Art Unit 2476	Page 3 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,898,204 B2	05-2005	Trachewsky et al.	370/445
*	B	US-6,888,844 B2	05-2005	Mallory et al.	370/466
*	C	US-6,891,881 B2	05-2005	Trachewsky et al.	375/143
*	D	US-6,954,800 B2	10-2005	Mallory, Tracy D.	709/240
*	E	US-6,975,655 B2	12-2005	Fischer et al.	370/516
*	F	US-6,985,453 B2	01-2006	Lundby et al.	370/311
*	G	US-6,988,236 B2	01-2006	Ptasinski et al.	714/758
*	H	US-6,993,101 B2	01-2006	Trachewsky et al.	375/343
*	I	US-7,000,031 B2	02-2006	Fischer et al.	709/248
*	J	US-7,020,110 B2	03-2006	Walton et al.	370/334
*	K	US-7,035,285 B2	04-2006	Holloway et al.	370/474
*	L	US-7,050,759 B2	05-2006	Gaal et al.	455/67.13
*	M	US-7,388,853 B2	06-2008	Ptasinski et al.	370/338

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/084,019	Applicant(s)/Patent Under Reexamination TIEDEMANN ET AL.	
	Examiner VENKATESH HALIYUR	Art Unit 2476	Page 4 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,406,106 B2	07-2008	Mallory, Tracy D.	370/522
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.